

**Search Notes**

Application/Control No.

10/786,164

Examiner

Alvin C. Chin-Shue

Applicant(s)/Patent under  
Reexamination

BEAN ET AL.

Art Unit

3634

**SEARCHED**

Class	Subclass	Date	Examiner
	<i>update</i>	<i>3.15.06</i>	<i>AS</i>

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR